Rochester Electronics

REI Datasheet

AM27S41, AM27S41A, AM27PS41

16,384-Bit (4,096x4) Bipolar PROM

The AM27S41 (4,096 words by 4 bits) is a Schottky TTL Programmable Read-Only Memory (PROM).

This device has three-state outputs compatible with low-power Schottky bus standards capable of satisfying the requirements of a variety of microprogrammable controls, mapping functions, code conversion, or logic replacement. Easy word-depth expansion is facilitated by active LOW ($\overline{G_1}$ & $\overline{G_2}$) output enables.

Rochester Electronics Manufactured Components

Rochester branded components are manufactured using either die/wafers purchased from the original suppliers or Rochester wafers recreated from the original IP. All recreations are done with the approval of the OCM.

Parts are tested using original factory test programs or Rochester developed test solutions to guarantee product meets or exceeds the OCM data sheet.

Quality Overview

- ISO-9001
- AS9120 certification
- Qualified Manufacturers List (QML) MIL-PRF-38535
    - Class Q Military
    - Class V Space Level
- Qualified Suppliers List of Distributors (QSLD)
    - Rochester is a critical supplier to DLA and meets all industry and DLA standards.

Rochester Electronics, LLC is committed to supplying products that satisfy customer expectations for quality and are equal to those originally supplied by industry manufacturers.

The original manufacturer's datasheet accompanying this document reflects the performance and specifications of the Rochester manufactured version of this device. Rochester Electronics guarantees the performance of its semiconductor products to the original OEM specifications. 'Typical' values are for reference purposes only. Certain minimum or maximum ratings may be based on product characterization, design, simulation, or sample testing.

Am27S41/27S41A/27PS41

16,384-Bit (4,096x4) Bipolar PROM

Advanced Micro Devices

DISTINCTIVE CHARACTERISTICS

- Ultra-fast access time "A" version (35 ns Max.)
- Platinum-Silicide fuses guarantee high reliability, fast programming and exceptionally high programming yields (typ > 98%)
- AC performance is factory tested utilizing programmed test words and columns
- Voltage and temperature compensated providing extremely flat AC performance over military range
- Member of generic PROM series utilizing standard programming algorithm

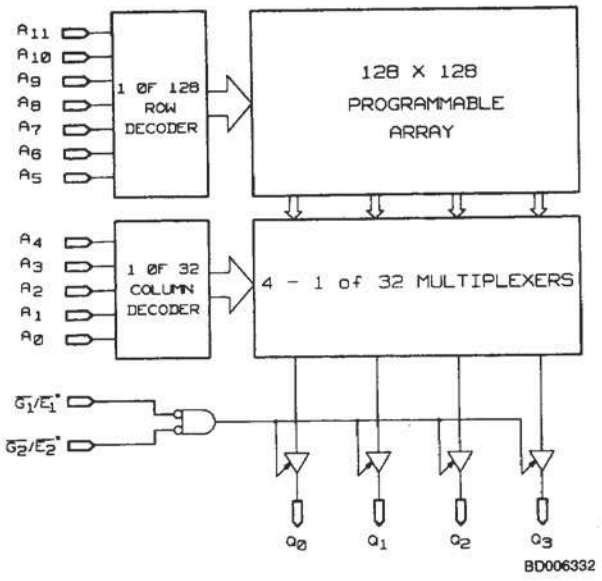
GENERAL DESCRIPTION

The Am27S41 (4,096 words by 4 bits) is a Schottky TTL Programmable Read-Only Memory (PROM).

This device has three-state outputs compatible with low-power Schottky bus standards capable of satisfying the requirements of a variety of microprogrammable controls, mapping functions, code conversion, or logic replacement. Easy word-depth expansion is facilitated by active LOW ($\overline{G_1}$ & $\overline{G_2}$) output enables.

As an APL product, this device is also offered in a power-switched version, the Am27PS41.

BLOCK DIAGRAM



*E nomenclature applies only to Am27PS power-switched version.

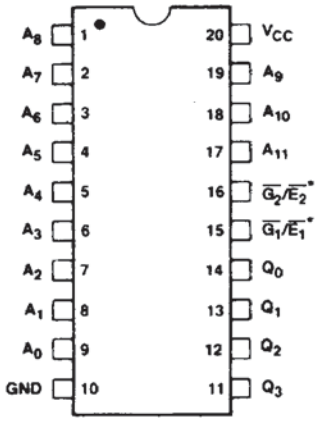
PRODUCT SELECTOR GUIDE

Part Number	Am27S41A		Am27S41		Am27PS41
Address Access Time	35 ns	50 ns	50 ns	65 ns	65 ns
Operating Range	C	M	C	M	M

Publication # 02122 Rev. D Amendment /0
Issue Date: January 1989

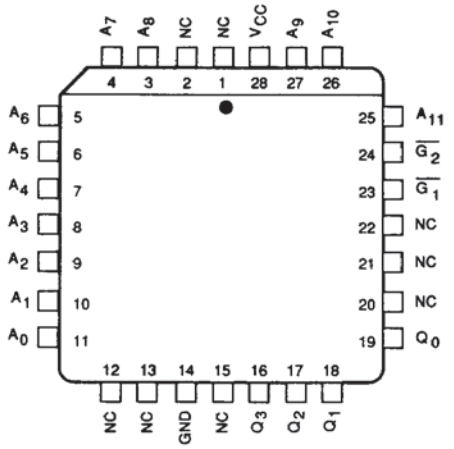
CONNECTION DIAGRAMS
Top View

DIPs



CD000412

PLCC

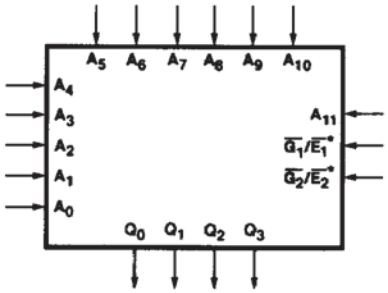


02122-001A

CD011750

Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



LS000043

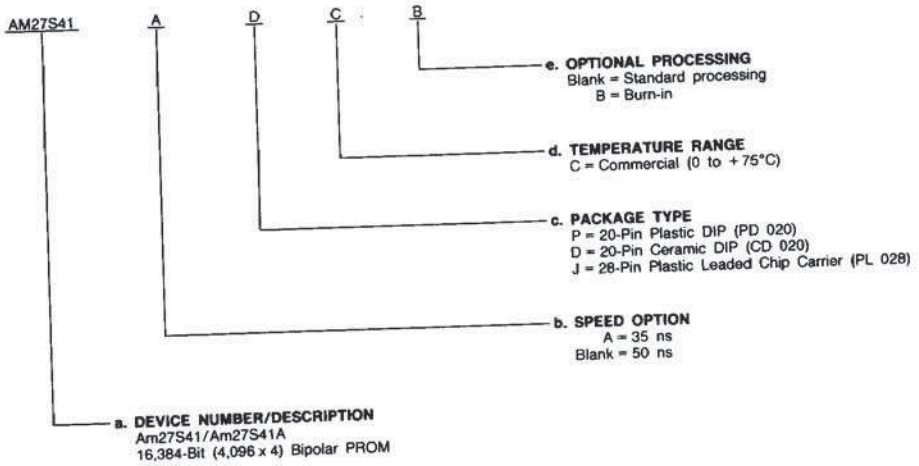
*E nomenclature applies only to Am27PS power-switched version.

ORDERING INFORMATION

Standard Products

AMD standard products are available in several packages and operating ranges. The order number (Valid Combination) is formed by a combination of:

a. Device Number
b. Speed Option (if applicable)
c. Package Type
d. Temperature Range
e. Optional Processing



Valid Combinations	
AM27S41	PC, PCB, DC, DCB, JC, JCB
AM27S41A	

Valid Combinations

Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations, to check on newly released combinations, and to obtain additional data on AMD's standard military grade products.

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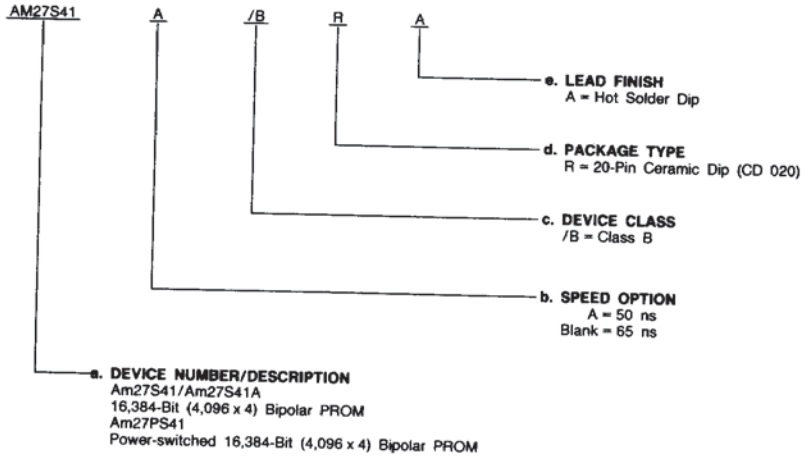
MILITARY ORDERING INFORMATION

APL Products

AMD products for Aerospace and Defense applications are available in several packages and operating ranges. APL (Approved Products List) products are fully compliant with MIL-STD-883C requirements. The order number (Valid Combination) for APL products is formed by a combination of: **a. Device Number**
b. Speed Option (if applicable)
c. Device Class
d. Package Type
e. Lead Finish



Valid Combinations	
AM27S41	/BRA
AM27S41A	
AM27PS41	

Valid Combinations

Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations or to check for newly released valid combinations.

Group A Tests

Group A tests consist of Subgroups 1, 2, 3, 7, 8, 9, 10, 11.

MILITARY BURN-IN

Military burn-in is in accordance with the current revision of MIL-STD-883, Test Method 1015, Conditions A through E. Test conditions are selected at AMD's option.

PIN DESCRIPTION

$A_0 - A_{11}$ Address Inputs
The 12-bit field presented at the address inputs selects one of 4,096 memory locations to be read from.

$Q_0 - Q_3$ Data Output Port
The outputs whose state represents the data read from the selected memory locations.

$\overline{G_1}$, $\overline{G_2}$ Output Enable
Provides direct control of the Q-output, three-state buffers. Outputs disabled forces all outputs to a floating or high-impedance state. On power-switched version, the disabled state reduces the I_{CC} to I_{CCD}.

Enable = $\overline{G_1} \cdot \overline{G_2}$

Disable = $\overline{\overline{G_1} \cdot \overline{G_2}}$

$= G_1 \cdot G_2$

V_{CC} Device Power Supply Pin
The most positive of the logic power supply pins.

GND Device Power Supply Pin
The most negative of the logic power supply pins.

FUNCTIONAL DESCRIPTION

Power Switching

The Am27PS41 is a power-switched device, When the chip is selected, important internal currents increase from small idling or standby values to their larger selected values. This transition occurs very rapidly, meaning that access times from the powered-down state are only slightly slower than from the powered-up state. Deselected, I_{CC} is reduced to half its full operating amount . Due to this unique feature, there are special considerations which should be followed in order to optimize performance:

1. When the Am27PS41 is selected by a low level on $\overline{E_1}$, a current surge is placed on the V_{CC} supply due to the power-up feature in order to minimize the effects of this current transient, it is recommended that a 0.1 μf ceramic capacitor be connected from pin 20 to pin 10 at each device. (See Figure 1.)

2. Address access time (TAVQ1) can be optimized if a chip enable set-up time (TEVAV) of greater than 25 ns is ovserved. Negative set-up times on chip enable (TEVAV < 0) should be avoided. (For typical and worse case characteristics, see Figures 2A and 2B.)

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ABSOLUTE MAXIMUM RATINGS

Storage Temperature ..... −65 to +150°C
Ambient Temperature with
Power Applied ..... −55 to +125°C
Supply Voltage ..... −0.5 V to +7.0 V
DC Voltage Applied to Outputs
(Except During Programming) ..... −0.5 V to +V_{CC} Max.
DC Voltage Applied to Outputs
During Programming ..... 21 V
Output Current into Outputs During
Programming (Max. Duration of 1 sec) ..... 250 mA
DC Input Voltage ..... −0.5 V to + 5.5 V
DC Input Current ..... −30 mA to +5 mA

OPERATING RANGES

Commercial (C) Devices
Ambient Temperature (T_A) ..... 0 to +75°C
Supply Voltage (V_{CC}) ..... +4.75 V to +5.25 V

Military (M) Devices
Case Temperature (T_C) ..... −55 to +125°C
Supply Voltage (V_{CC}) ..... +4.5 V to +5.5 V

Operating ranges define those limits between which the functionality of the device is guaranteed.

Military Products 100% tested at T_C = +25°C, +125°C, and −55°C.

DC CHARACTERISTICS over operating ranges unless otherwise specified (for APL Products, Group A, Subgroups 1, 2, 3 are tested unless otherwise noted)

Parameter Symbol	Parameter Description	Test Conditions		Min.	Typ.	Max.	Unit
V_{OH}	Output HIGH Voltage	V_{CC} = Min., I_{OH} = −2.0 mA V_{IN} = V_{IH} or V_{IL}		2.4			V
V_{OL}	Output LOW Voltage	V_{CC} = Min., I_{OL} = 16 mA V_{IN} = V_{IH} or V_{IL}	COM'L			0.45	V
			MIL			0.50	
V_{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs (Note 3)		2.0			V
V_{IL}	Input LOW Level	Guaranteed input logical LOW voltage for all inputs (Note 3)				0.8	V
I_{IL}	Input LOW Current	V_{CC} = Max., V_{IN} = 0.45 V				−0.250	mA
I_{IH}	Input HIGH Current	V_{CC} = Max., V_{IN} = V_{CC}				40	μA
I_{SC}	Output Short-Circuit Current	V_{CC} = Max., V_{OUT} = 0.0 V (Note 1)	COM'L	−20		−90	mA
			MIL	−15		−90	
I_{CC}	Power Supply Current	V_{CC} = Max. All inputs = 0.0 V	COM'L			165	mA
			MIL			170	
I_{CCD}*	Am27PS Version Power Down Supply Current	V_{CC} = Max $\overline{VE_1}$ = 2.4 V, All other inputs = 0.0 V				85	mA
V_I	Input Clamp Voltage	V_{CC} = Min., I_{IN} = −18 mA				−1.2	V
I_{CEX}	Output Leakage Current	V_{CC} = Max. $\overline{VG_1}$ = 2.4 V	V_O = V_{CC}			40	μA
			V_O = 0.4 V			−40	
C_{IN}	Input Capacitance	V_{IN} = 2.0 V @ f = 1 MHz (Note 2) V_{CC} = 5 V, T_A = 25°C			5.0		pF
C_{OUT}	Output Capacitance	V_{OUT} = 2.0 V @ f = 1 MHz (Note 2) V_{CC} = 5 V, T_A = 25°C			8.0		

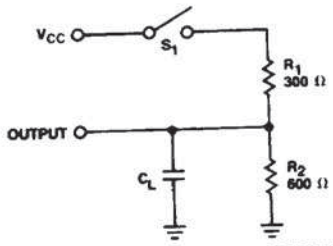
Notes: 1. Not more than one output should be shorted at a time. Duration of the short circuit test should not be more than one second.
2. These parameters are not 100% tested, but are evaluated at initial characterization and at any time the design is modified where capacitance may be affected.
3. V_{IL} and V_{IH} are input conditions of output tests and are not themselves directly tested. V_{IL} and V_{IH} are absolute voltages with respect to device ground and include all overshoots due to system and/or tester noise. Do not attempt to test these values without suitable equipment.
* For Am27PS41, APL only.

SWITCHING CHARACTERISTICS over operating ranges unless otherwise specified (for APL Products, Group A, Subgroups 9, 10, 11 are tested unless otherwise noted*)

No.	Parameter Symbol	Parameter Description	Version	27S Version				27PS Version		Unit
				COM'L		MIL		MIL		
				Min.	Max.	Min.	Max.	Min.	Max.	
1	TAVQV	Address Valid to Output Valid Access Time	A		35		50			ns
			STD		50		65		65	
2	TGVQZ	Delay from Output Enable Valid to Output Hi-Z	A		25		30			ns
			STD		25		30		30	
3	TGVQV	Delay from Output Enable Valid to Output Valid	A		25		30			ns
			STD		25		30		85	
4	TAVQV1	Power Switched Address Valid to Output Valid Access Time (Am27PS Versions only)	A							ns
			STD						85	

See also Switching Test Circuit.
Notes: 1. Tests are performed with input transition time of 5 ns or less, timing reference levels of 1.5 V, and input pulse levels of 0 to 3.0 V.
*Subgroups 7 and 8 apply to functional tests.

SWITCHING TEST CIRCUIT



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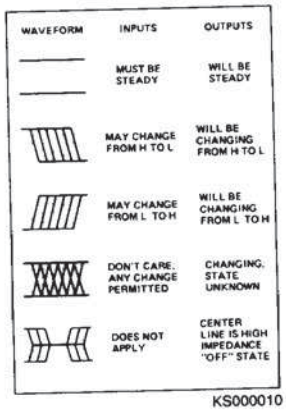
Notes: 1. TAVQV is tested with switch S_1 closed and C_L = 50 pF. TEVAV is defined as chip enable setup time.
2. For the three-state output, TGVQV is tested with C_L = 50 pF to the 1.5 V level; S_1 is open for high-impedance to HIGH tests and closed for high-impedance to LOW tests. TGVQZ is tested with C_L = 5 pF. HIGH to high-impedance tests are made with S_1 open to an output voltage of steady state HIGH – 0.5 V; LOW to high-impedance tests are made with S_1 closed to the steady state LOW + 0.5 V level.

SWITCHING WAVEFORMS

KEY TO SWITCHING WAVEFORMS



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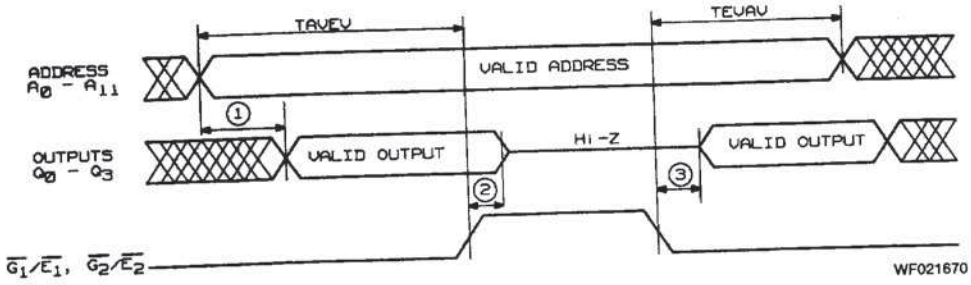

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